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Control No. PCN-23281 July 27, 2023

| | PROD | UCT/PROCESS CHANGE NOTI | FICATION | |
|-----------------|--------|--|----------|---|
| TYPE OF CHANGE: | Design | Manufacturing | Other | |
| | | ch Power Integrations policy o e, please contact your regiona | | • |

DESCRIPTION OF CHANGE

Seiko Epson, Sakata, Japan 6-inch wafer fabrication is added as an alternative wafer fab production line of the power-switch wafers for the product families listed in the table below. Seiko Epson, Sakata, Japan is one of the qualified wafer fabrication sites of Power Integrations products.

REASON FOR CHANGE

Improve manufacturing flexibility and diversification of manufacturing sites.

PRODUCTS AFFECTED

| Product Family | Part Numbers | Package |
|-----------------|--|------------|
| HiperPFS-5 | PFS5175F-TL, PFS5275F-TL | InSOP-T28F |
| InnoSwitch3-CP | INN3270C0255-H114-TL, INN3270C0255-H215-TL, INN3270C-H114-TL, INN3270C-H203-TL, INN3270C-H215-TL, INN3270C-H217-TL, INN3270C-H235-TL, SC1936C-H217-TL, SC1957C-H004-TL, SC1957C-H005-TL, SC1972C-H058-TL | InSOP-24D |
| InnoSwitch3-EP | INN3670C-H605-TL, INN3670C-H606-TL, INN3670C-H615-TL, SC1936C-H114-TL, SC1936C-H215-TL, SC1936C-H605-TL, SC1936C-H606-TL | InSOP-24D |
| InnoSwitch3-MX | INN3470C-TL | InSOP-24D |
| InnoSwitch3-PD | INN3870C-H170-TL, INN3870C-H801-TL, INN3870C-H805-TL, SC2300C-H099-TL | InSOP-24D |
| InnoSwitch3-Pro | INN3370C0255-H302-TL, INN3370C-H302-TL, INN3370C-H309-TL, INN3370C-H310-TL, INN3370C-H313-TL, SC1922C-TL,SC1923C-H006-TL, SC1952C-H302-TL, SC1981C-TL, SC1998C-H057-TL | InSOP-24D |
| InnoSwitch4-CZ | INN4075C-H181-TL, INN4075C-H182-TL, INN4075C-H183-TL, INN4075C-H185-TL, INN4075C-H186-TL, INN4175C-H187-TL, INN4175C-H188-TL, INN4175C-H189-TL, INN4175C-H190-TL, INN4175C-H191-TL, INN4175C-H192-TL, SC3600C-H078-TL, SC3602C-H163-TL | InSOP-24D |
| InnoSwitch4-Pro | INN4375F-H341-TL, INN4475F-H341-TL, INN4575F-H342-TL, INN4675F-H342-TL | InSOP-T28D |
| LYTSwitch-6 | LYT6070C-H125-TL, LYT6070C-H127-TL, LYT6070C-H129-TL, LYT6070C-H131-TL, LYT6070C-TL | InSOP-24D |

QUALIFICATION STATUS

See Appendix 1 for the qualification report.

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EFFECT ON CUSTOMER

No adverse impact is expected in customers' applications. The product will be guaranteed to meet the datasheet limits.

EFFECTIVE DATE

October 27, 2023. This date is subject to change. Products fabricated at the current locations will continue to be shipped after the addition.

SAMPLE AVAILABILITY

Samples will be available 6 weeks from the date of request. Please send requests for samples within two weeks after receipt of this notification to the local Power Integrations sales office. For manufacturers that request samples, an accommodation will be made in order to allow time of customer's qualification in a case-specific manner.

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Appendix 1 Reliability Engineering Qualification Report Qualification Project: E221502

Project Title: Seiko Epson, Sakata Fab Power-switch Qualification for Multiple Product Families

Qual Summary:

Reliability testing was performed to qualify power-switch wafer fabrication for HiperPFS-5 products, multiple InnoSwitch3 families, multiple InnoSwitch4 families and LYTSwitch-6 products in the previously qualified Seiko Epson wafer fab in Sakata, Japan. Three representative product qual lots were subjected to a full suite of reliability stress tests with passing results obtained. Based on these results, Seiko Epson, Sakata is qualified for power-switch wafer fabrication for above-mentioned products.

Qualification Vehicles: INN4177C, INN3379C, INN3479C

Reliability Test Descriptions and Conditions

| Test Name | Conditions | Reference Specification |
|---------------------------------------|--|-------------------------|
| DOPL (Dynamic Operating Life Test) | Tj=125°C, Vd_peak=650V, Vsupply = VBP | EIA/JESD22-A108 |
| HALT (Humidity Accelerated Life Test) | Vd = 520V ; Tj=115°C, 85% RH | Internal Standard |
| THBT (Temperature Humidity Bias Test) | 85°C, 85% RH, Vd=100V | EIA/JESD22-A101 |
| TMCL (Temperature Cycle, Air to Air) | -40°C to +125°C, air to air | EIA/JESD22-A104 |
| HTSL (High Temperature Storage Life) | Ta=150°C, unbiased | EIA/JESD22-A103 |
| MSL3 Preconditioning | 24-hr 150°C Bake +40-hr 60°C, 60% RH Moisture Soak + 3 Passes 260°C Solder Reflow | EIA/JESD22-A113 |

DOPL (Dynamic Operating Life)

| Product | Lot # | Wafer Fab | Test Duration | No. Failures/Sample Size |
|----------|---------|---------------------|-------------------|--------------------------|
| INN3379C | MBM782F | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 45 |
| INN3379C | MBM782G | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 45 |
| INN4177C | MDB524A | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 45 |

HALT (Humidity Accelerated Life Test)

| Product | Lot # | Wafer Fab | Test Duration | No. Failures/Sample Size |
|----------|---------|---------------------|-------------------|--------------------------|
| INN3479C | M9V136A | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 20 |
| INN3379C | MBM782E | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 20 |
| INN3379C | MBM782F | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 20 |

THBT (Temperature Humidity Bias)

| Product | Lot # | Wafer Fab | Test Duration | No. Failures/Sample Size |
|----------|---------|---------------------|-------------------|--------------------------|
| INN3379C | MBM782E | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 45 |
| INN3379C | MBM782F | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 45 |
| NN3379C | MBM782G | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 45 |

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HTSL (High Temperature Storage Life)

| Product | Lot # | Wafer Fab | Test Duration | No. Failures/Sample Size |
|----------|---------|---------------------|-------------------|--------------------------|
| INN3379C | MBM782E | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 45 |
| INN3379C | MBM782F | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 45 |
| INN3379C | MBM782G | Seiko Epson, Sakata | MSL3 + 1000 hours | 0 / 45 |

TMCL (Temperature Cycling)

| Product | Lot # | Wafer Fab | Test Duration | No. Failures/Sample Size |
|----------|---------|---------------------|-------------------|--------------------------|
| INN3379C | MBM782E | Seiko Epson, Sakata | MSL3 + 850 cycles | 0 / 45 |
| INN3379C | MBM782F | Seiko Epson, Sakata | MSL3 + 850 cycles | 0 / 45 |
| INN3379C | MBM782G | Seiko Epson, Sakata | MSL3 + 850 cycles | 0 / 45 |

Conclusion: Based on passing qualification results, Seiko Epson, Sakata is qualified for power-switch wafer fabrication for all products identified in the above "Products Affected" table.

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CUSTOMER ACKNOWLEDGEMENT

Power Integrations requests you acknowledge the receipt of the above-mentioned PCN. If no acknowledgment is received within 30 days of this notification, Power Integrations will assume the change is acceptable. Lack of any additional response within 90 days of this notification further constitutes acceptance of the change.

Power Integrations reserves the right to ship either version manufactured after the effective date.

The indicated Product/Process Change Notification was received by the undersigned authority.

Please email this signed form to pcn@power.com specifying the PCN# in the subject.

If you have any questions or need further assistance, please contact your regional Power Integrations sales office. Otherwise, please check the box below, acknowledging the receipt of the PCN.

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